

# Search Notes



Application/Control No.

10/788,667

Examiner

Hiep Nguyen

Applicant(s)/Patent under  
Reexamination

FERIANZ ET AL.

Art Unit

2816

## SEARCHED

Class	Subclass	Date	Examiner
327	108	03.28.05	<i>HN</i>
	109	—	—
	110	↓	↓
326	82		
	83		
	86		
	87		
	91	↓	↓

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST See attachment	03.28.05	<i>HN</i>